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7590	12/11/2008		EXAMINER	
Moser Patterson & Sheridan Zimmermann & Partner Suite 1500 3040 Post Oak Boulevard Houston, TX 77056			VELEZ, ROBERTO	
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Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Continuation Sheet

1. Regarding claim 50, Applicant argues that Kuwashiro does not teach or suggest providing an input terminal of a drive circuit directly or via another component with input signals via an arrangement of test contact areas to generate a test pattern on a matrix of picture element as set forth in claim 50. The Examiner respectfully disagrees. Kuwashiro shows (Fig. 3) wherein the test contacts [651-2, 651-2] are electrically connected to dummy pads [731-1, 731-2]. Dummy pads [731-1, 731-2] are electrically connected to interconnections [753-1, 753-2]. Interconnections [753-1, 753-2] are electrically connected to data interconnections [783]. Interconnections [783] are also electrically connected to operational contact areas [641]. Test pattern (horizontal clock signal (CKH), horizontal start signal (STH) or digital image data (DDSR)) will be transmitted through interconnections [783] to the display device in order to detect if desired signals are being supplied. Since the test pattern supplied to interconnection 783 will be passing through test contacts [651-2, 651-2] and the final destination of the test pattern is the display device, broadly, it can interpreted that Kuwashiro discloses providing an input terminal of a drive circuit with input signals via an arrangement of test contact areas to generate a test pattern on a matrix of picture element (Col. 6, Ln 36 through Col. 7, Ln 67). Therefor, Kuwashiro does teach or suggest providing an input terminal of a drive circuit directly or via another component with input signals via an arrangement of test contact areas to generate a test pattern on a matrix of picture element as set forth in claim 50.

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2. Regarding claim 50, Applicant also argues that Kuwashiro also does not teach or suggest testing picture elements of a matrix of picture elements as set forth in claim 50. The Examiner respectfully disagrees. Kuwashiro discloses if a defect is present in the **image displayed** on the active matrix liquid crystal display 1, a probe makes contact with the dummy terminals 651-1, 651-2 successively to see if desired signals are being supplied (Col. 7, Ln 43-47). Any ordinary skill in the art would recognize that the elements displaying an image would be the picture elements [2]. In other words, Kuwashiro implicitly discloses testing the picture elements by detecting if desired signals are being supplied. Therefor, Kuwashiro does teach or suggest testing picture elements of a matrix of picture elements as set forth in claim 50.

/Ha T. Nguyen/

Supervisory Patent Examiner, Art Unit 2829